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Road vehicles — Local Interconnect Network (LIN) —

Part 7: Electrical Physical Layer (EPL) conformance test specification

Véhicules routiers — Réseau Internet local (LIN) —

*Partie 7: Spécification d'essai de conformité de la couche électrique
physique (EPL)*



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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights. Details of any patent rights identified during the development of the document will be in the Introduction and/or on the ISO list of patent declarations received (see www.iso.org/patents).

Any trade name used in this document is information given for the convenience of users and does not constitute an endorsement.

For an explanation on the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT) see the following URL: www.iso.org/iso/foreword.html.

The committee responsible for this document is ISO/TC 22, *Road vehicles*, Subcommittee SC 31, *Electrical and electronic equipment*.

A list of all parts in the ISO 17987 series can be found on the ISO website.

Introduction

The LIN protocol as proposed is an automotive focused low-speed universal asynchronous receiver transmitter (UART)-based network. Some of the key characteristics of the Local Interconnect Network (LIN) protocol are signal-based communication, schedule table-based frame transfer, master/slave communication with error detection, node configuration and diagnostic service transportation.

The LIN protocol is for low-cost automotive control applications, for example, door module and air condition systems. It serves as a communication infrastructure for low-speed control applications in vehicles by providing

- signal-based communication to exchange information between applications in different nodes,
- bitrate support from 1 kbit/s to 20 kbit/s,
- deterministic schedule table-based frame communication,
- network management that wakes up and puts the LIN cluster into sleep mode in a controlled manner,
- status management that provides error handling and error signalling,
- transport layer that allows large amount of data to be transported (such as diagnostic services),
- specification of how to handle diagnostic services,
- electrical physical layer specifications,
- node description language describing properties of slave nodes,
- network description file describing behaviour of communication, and
- application programmer's interface.

ISO 17987 (all parts) is based on the open systems interconnection (OSI) basic reference model as specified in ISO/IEC 7498-1 which structures communication systems into seven layers.

The OSI model structures data communication into seven layers called (top down) *application layer* (layer 7), *presentation layer*, *session layer*, *transport layer*, *network layer*, *data link layer* and *physical layer* (layer 1). A subset of these layers is used in ISO 17987 (all parts).

ISO 17987 (all parts) distinguishes between the services provided by a layer to the layer above it and the protocol used by the layer to send a message between the peer entities of that layer. The reason for this distinction is to make the services, especially the application layer services and the transport layer services, reusable also for other types of networks than LIN. In this way, the protocol is hidden from the service user and it is possible to change the protocol if special system requirements demand it.

ISO 17987 (all parts) provides all documents and references required to support the implementation of the requirements related to the following:

- ISO 17987-1: This part provides an overview of the ISO 17987 (all parts) and structure along with the use case definitions and a common set of resources (definitions, references) for use by all subsequent parts.
- ISO 17987-2: This part specifies the requirements related to the transport protocol and the network layer requirements to transport the PDU of a message between LIN nodes.
- ISO 17987-3: This part specifies the requirements for implementations of the LIN protocol on the logical level of abstraction. Hardware related properties are hidden in the defined constraints.
- ISO 17987-4: This part specifies the requirements for implementations of active hardware components which are necessary to interconnect the protocol implementation.

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- ISO/TR 17987-5: This part specifies the LIN application programmers interface (API) and the node configuration and identification services. The node configuration and identification services are specified in the API and define how a slave node is configured and how a slave node uses the identification service.
- ISO 17987-6: This part specifies tests to check the conformance of the LIN protocol implementation according to ISO 17987-2 and ISO 17987-3. This comprises tests for the data link layer, the network layer and the transport layer.
- ISO 17987-7: This part specifies tests to check the conformance of the LIN electrical physical layer implementation (logical level of abstraction) according to ISO 17987-4.